

FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office List of Documents Cited by Applicant		Application No.:	10/615,842
		Filing Date:	July 10, 2003
		First Named Inventor:	Oh
		Group:	1795
		Examiner:	Phasge, Arun S.
		Attorney Docket No.:	421/170/8/2 CIP

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*Examiner Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.